

#### **TECHNOLOGY**

# Enhanced Tuning of i-line Fabricated Optoelectronics for Greatly Increased Performance

### **OVERVIEW**

#### Background

i-line photolithography is a staple of modern microelectronics manufacturing, particularly optoelectronic devices such as laser diodes. As such, it is a very established and mature technology. However, microscale roughness is a known issue with i-line manufacturing, and devices manufactured with this method are ultimately constrained in performance due to this roughness, such as reduced optical efficiency in optical waveguides.

#### Innovative Technology

Researchers at the University of Maryland have meticulously tuned an i-line photolithography process to reduce the surface roughness of the semiconductor sidewalls in microelectronic and photonic devices. Using this process, typical roughness was reduced from 64 nm peak-to-peak RMS in the standard process to 10 nm peak-to-peak RMS in the new process. Consequently, the typical linear optical loss in a 0.8 µm wide optical waveguide was reduced from 4.7 dB/cm to 0.7 dB/cm in the new process, a significant improvement. This new process will extend the life and thus increase the value of products currently manufactured using i-line photolithography.

#### Advantages

- Fabrication processes easily accessible in a standard fab
- o Extended life of installed i-line photolithography tool
- Significantly reduced sidewall surface roughness in etched structures
- o Improved optical efficiency of lasers and waveguides
- o Lower electrical power consumption of devices
- o Improved quality factor in resonators (optical or mechanical)

#### **Applications**

- Optoelectronics
- o Photonic integrated circuits (PIC)
- o Optical communications devices
- o Semiconductor lasers and waveguides
- Micro Electro Mechanical Systems (MEMS)

## **CONTACT INFO**

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# **Additional Information**

# **INSTITUTION**

University of Maryland, College Park

# **PATENT STATUS**

Pending

# **LICENSE STATUS**

Available for exclusive license

# **CATEGORIES**

Microelectronics

## **EXTERNAL RESOURCES**

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